

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-957-04	SERIAL NO. 10/669,564		
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT T. MATSUURA et al			
				FILING DATE September 25, 2003	GROUP		
U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)	
PN	AA 5,026,669	06/25/91	Shinohara	X	X	/	
	AB 5,327,104	07/05/94	Kikushima			/	
	AC 5,731,231	03/24/98	Miyajima			/	
	AD 5,973,395	10/26/99	Suzuki et al			/	
	AE 6,208,020	03/27/01	Minamio et al			/	
	AF 6,399,423	06/2002	Matsuura et al			/	
PN	AG 6,208,020	03/2001	Minamio et al			/	
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
PN	AL 11-195743	07/21/99	Japan	1	1	<input type="checkbox"/>	<input type="checkbox"/>
PN	AM 2-240940	09/25/90	Japan	1	1	<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
PN	AR	"Semiconductor Assembling/Testing Technique of '99", Extra Issue of Monthly Semiconductor World, July 27, 1998.					
	AS						
	AT						
EXAMINER Sawada				DATE CONSIDERED 8/10/04			

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form next communication to applicant.